Wavevue Measurement Studio™ Software



The demand for high-frequency ICs is being driven by the growth of complex electronic systems with clock rates of >1 GHz (PCs, PDAs, wireless LANs, Bluetooth chips). This increase in demand, together with the accelerated pace of device development, has put more emphasis on the need for commercial quality software tools. Wavevue is an integral part of a complete Cascade Microtech test system solution that combines the necessary tools to fully characterize an on-wafer RF device.

Benefits of this test software:

- significantly improved characterization engineering productivity
- reduced modeling and design cycle times
- substantial time and cost savings
- the most advanced technical test capability available

CASCADE® MICROTECH

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Solution Architecture

Cascade Microtech

- Wavevue™ Characterization software
- WinCal™ Calibration software
- State-of-the-art 200 mm and 300 mm probe stations with Nucleus control software
- High performance characterization probes
- High performance on-wafer calibration standards

Agilent

Vector Network Analyzer (one of these models):
Agilent PNA 835x or 836x
Agilent 8510
Agilent 87xx

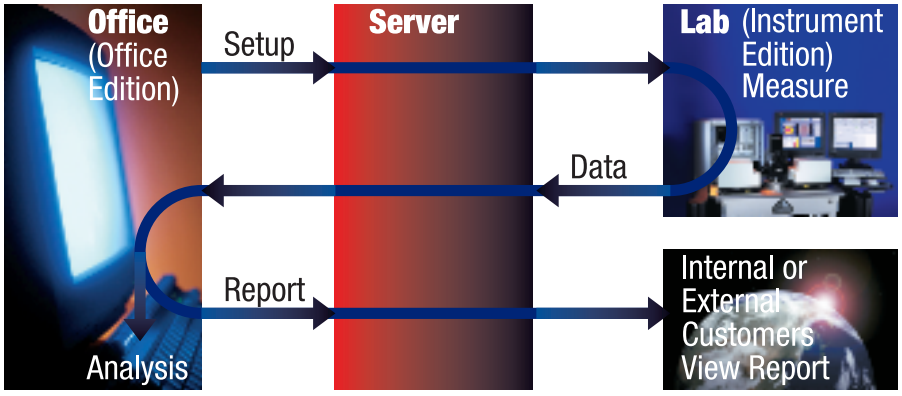
DC Bias Power Supplies:
Agilent 4142 A,B
Agilent 4155 A,B,C
Agilent 4156 A,B,C
Agilent 603X
Agilent 662X
Agilent 6661X
Agilent 6663X
Agilent E363X

The Wavevue solution expands the technical frontier through:

- **Enterprise vision: Instrument and Office Editions** provide division of tasks between the desktop and capital equipment. Setups move from the desktop to the test equipment and the test results return to the desktop for evaluation and report generation.
- **Modular architecture** reduces cost of ownership and protects long-term investment by offering future expandability. Consistent user interface for multiple test types reduces training and support requirements.
- **Project based user environment** provides a single point of focus that combines the components necessary to execute a measurement test plan.
- **Flexible and instant report generation and export** brings increased productivity in application data workflow.
- **Scripts generated automatically from the GUI,** yet advanced users can modify them as necessary to generate sophisticated test sequences.
- **Individualized login** provides a means to set the bounds for functional access and preserve individual preferences.
- **Data management**
- **Setup wizards** for setting up test plans and DC bias leads to increased measurement accuracy, repeatability and productivity.
- **On-wafer test integration**: complete integration to Cascade Microtech's Nucleus prober control software and WinCal calibration software on a single PC.

Supporting Literature

Data Sheets:
Nucleus (NUCLEUS-DS-0901)
WinCal (WINCAL-DS-0602)
Wavevue (WAVEVUE-DS-0602)
Summit Stations (RFMICRO-DS-1001)
ISS (ISS-DS-0602)
Probe head selection guide (RFPSG-1000)
LRM & LRRM calibrations app note (AR114)
Probe training video CD ROM (124-986)



CASCADE® MICROTECH

Innovating Test Technologies® for better measurements faster

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